

Irish Standard I.S. EN ISO 25178-603:2013

Geometrical product specifications (GPS) -Surface texture: Areal - Part 603: Nominal characteristics of non-contact (phaseshifting interferometric microscopy) instruments (ISO 25178-603:2013)

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# **EUROPEAN STANDARD**

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#### **English Version**

Geometrical product specifications (GPS) - Surface texture: Areal - Part 603: Nominal characteristics of non-contact (phaseshifting interferometric microscopy) instruments (ISO 25178-603:2013)

Spécification géométrique des produits (GPS) - État de surface: Surfacique - Partie 603: Caractéristiques nominales des instruments sans contact (microscopes interférométriques à glissement de franges) (ISO 25178-603:2013)

Geometrische Produktspezifikation (GPS) -Oberflächenbeschaffenheit: Flächenhaft - Teil 603: Merkmale von berührungslos messenden Geräten (phasenschiebende interferometrische Mikroskopie) (ISO 25178-603:2013)

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# EN ISO 25178-603:2013 (E)

Contents	Page
Foreword	3

EN ISO 25178-603:2013 (E)

#### **Foreword**

This document (EN ISO 25178-603:2013) has been prepared by Technical Committee ISO/TC 213 "Dimensional and geometrical product specifications and verification" in collaboration with Technical Committee CEN/TC 290 "Dimensional and geometrical product specification and verification" the secretariat of which is held by AFNOR.

This European Standard shall be given the status of a national standard, either by publication of an identical text or by endorsement, at the latest by April 2014, and conflicting national standards shall be withdrawn at the latest by April 2014.

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# I.S. EN ISO 25178-603:2013 INTERNATIONAL STANDARD

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# Geometrical product specifications (GPS) — Surface texture: Areal —

Part 603:

Nominal characteristics of non-contact (phase-shifting interferometric microscopy) instruments

Spécification géométrique des produits (GPS) — État de surface: Surfacique —

Partie 603: Caractéristiques nominales des instruments sans contact (microscopes interférométriques à glissement de franges)



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# ISO 25178-603:2013(E)

Con	tents		Page
Forew	ord		iv
Introd			
1	Scope		1
3	Terms 2.1 2.2 2.3 2.4 2.5	Terms and definitions related to all areal surface texture measurement methods  Terms and definitions related to x- and y-scanning systems  Terms and definitions related to optical systems  Terms and definitions related to optical properties of the workpiece  Terms and definitions specific to phase-shifting interferometric microscopy	181012
	3.1 3.2	General Influence quantities	13
Annex	A (info	rmative) Components of a phase-shifting interferometric (PSI) microscope	16
Annex	B (info	ormative) Phase-shifting interferometric (PSI) microscope — Theory of operation	ı17
Annex		rmative) Errors and corrections for phase-shifting interferometric nicroscopes	22
Annex	<b>D</b> (info	ormative) Relation to the GPS matrix model	25
Biblio	graphy		27

#### ISO 25178-603:2013(E)

#### **Foreword**

ISO (the International Organization for Standardization) is a worldwide federation of national standards bodies (ISO member bodies). The work of preparing International Standards is normally carried out through ISO technical committees. Each member body interested in a subject for which a technical committee has been established has the right to be represented on that committee. International organizations, governmental and non-governmental, in liaison with ISO, also take part in the work. ISO collaborates closely with the International Electrotechnical Commission (IEC) on all matters of electrotechnical standardization.

The procedures used to develop this document and those intended for its further maintenance are described in the ISO/IEC Directives, Part 1. In particular the different approval criteria needed for the different types of ISO documents should be noted. This document was drafted in accordance with the editorial rules of the ISO/IEC Directives, Part 2. www.iso.org/directives

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For an explanation on the meaning of ISO specific terms and expressions related to conformity assessment, as well as information about ISO's adherence to the WTO principles in the Technical Barriers to Trade (TBT) see the following URL: Foreword - Supplementary information

The committee responsible for this document is ISO/TC 213, *Dimensional and geometrical product specifications and verification.* 

ISO 25178 consists of the following parts, under the general title *Geometrical product specification (GPS)* — *Surface texture: Areal:* 

- Part 1: Areal surface texture drawing indication
- Part 2: Terms, definitions and surface texture parameters
- Part 3: Specification operators
- Part 6: Classification of methods for measuring surface texture
- Part 70: Material measures
- Part 71: Software measurement standards
- Part 601: Nominal characteristics of contact (stylus) instruments
- Part 602: Nominal characteristics of non-contact (confocal chromatic probe) instruments
- Part 603: Nominal characteristics of non-contact (phase-shifting interferometric microscopy) instruments
- Part 604: Nominal characteristics of non-contact (coherence scanning interferometric microscopy) instruments
- Part 605: Nominal characteristics of non-contact (point autofocus probe) instruments
- Part 606: Nominal characteristics of non-contact (focus variation microscopy) instruments
- Part 701: Calibration and measurement standards for contact (stylus) instruments
- Part 702 Calibration of non-contact (confocal chromatic probe) instruments

ISO 25178-603:2013(E)

— Part 703: Calibration and measurement standards for non-contact (interferometric) instruments

The following part is under preparation: Part 72: XML file format x3p

ISO 25178-603:2013(E)

# Introduction

This part of ISO 25178 is a Geometrical Product Specification standard and is to be regarded as a general GPS standard (see ISO/TR 14638). It influences the chain link 5 of the chain of standards on areal surface texture.

This part of ISO 25178 describes the metrological characteristics of phase-shifting interferometric (PSI) profile and areal surface texture measuring microscopes, designed for the measurement of surface topography maps. For more detailed information on the phase-shifting interferometry technique, see Annex A and Annex B.

The ISO/GPS Masterplan given in ISO /TR 14638 gives an overview of the ISO/GPS system of which this document is a part. The fundamental rules of ISO/GPS given in ISO 8015 apply to this document and the default decision rules given in ISO 14253-1 apply to specifications made in accordance with this document, unless otherwise indicated.

NOTE Portions of this document, particularly the informative clauses, may describe patented systems and methods. This information is provided only to assist users in understanding the operating principles of phase-shifting interferometry. This document is not intended to establish priority for any intellectual property, nor does it imply a license to any proprietary technologies that may be described herein.

# Geometrical product specifications (GPS) — Surface texture: Areal —

# Part 603:

# Nominal characteristics of non-contact (phase-shifting interferometric microscopy) instruments

### 1 Scope

This part of ISO 25178 describes the metrological characteristics of phase-shifting interferometric (PSI) profile and areal surface texture measuring microscopes.

#### 2 Terms and definitions

For the purposes of this document, the following terms and definitions apply.

#### 2.1 Terms and definitions related to all areal surface texture measurement methods

#### 2.1.1

#### areal reference

component of the instrument that generates a reference surface with respect to which the surface topography is measured

#### 2.1.2

### coordinate system of the instrument

right hand orthonormal system of axes (x, y, z) where

- (*x*, *y*) is the plane established by the areal reference of the instrument (note that there are optical instruments that do not possess a physical areal guide);
- z-axis is mounted parallel to the optical axis and is perpendicular to the (x, y) plane for an optical instrument; the z-axis is in the plane of the stylus trajectory and is perpendicular to the (x, y) plane for a stylus instrument

Note 1 to entry: Normally, the *x*-axis is the tracing axis and the *y*-axis is the stepping axis. (This note is valid for instruments that scan in the horizontal plane.)

Note 2 to entry: See also "specification coordinate system" [ISO 25178-2:2012, 3.1.2] and "measurement coordinate system" [ISO 25178-6:2010, 3.1.1].

SEE: Figure 1.



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